

## Title (en)

METHODS AND SYSTEMS FOR UTILIZING DESIGN DATA IN COMBINATION WITH INSPECTION DATA

## Title (de)

VERFAHREN UND SYSTEME ZUR VERWENDUNG VON ENTWURFSDATEN IN KOMBINATION MIT PRÜFDATEN

## Title (fr)

PROCEDES ET SYSTEMES PERMETTANT D'UTILISER DES DONNEES DE CONCEPTION EN COMBINAISON AVEC DES DONNEES D'INSPECTION

## Publication

**EP 1955225 A4 20091104 (EN)**

## Application

**EP 06850792 A 20061120**

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- US 2006061113 W 20061120
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- US 56173506 A 20061120

## Abstract (en)

[origin: WO2007120279A2] Various methods and systems for utilizing design data in combination with inspection data are provided. One computer-implemented method for binning defects detected on a wafer includes comparing portions of design data proximate positions of the defects in design data space. The method also includes determining if the design data in the portions is at least similar based on results of the comparing step. In addition, the method includes binning the defects in groups such that the portions of the design data proximate the positions of the defects in each of the groups are at least similar. The method further includes storing results of the binning step in a storage medium.

## IPC 8 full level

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## CPC (source: EP KR)

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## Citation (search report)

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- [A] EP 0370322 A2 19900530 - SCHLUMBERGER TECHNOLOGIES INC [US]
- [A] US 2005198602 A1 20050908 - BRANKNER KEITH J [US]
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- See references of WO 2007120280A2

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**US 2006061112 W 20061120;** EP 06850792 A 20061120; IL 19152708 A 20080518; IL 23023513 A 20131229; IL 23026013 A 20131231; IL 23428914 A 20140825; IL 23429014 A 20140825; IL 23431614 A 20140826; IL 23431714 A 20140826; IL 23431814 A 20140826; IL 23431914 A 20140826; IL 23434314 A 20140827; IL 23434414 A 20140827; IL 23434514 A 20140827; IL 23434614 A 20140827; IL 25318917 A 20170627; JP 2008541507 A 20061120; JP 2012111262 A 20120515; JP 2013134798 A 20130627; JP 2013134802 A 20130627; JP 2014077804 A 20140404; JP 2014255556 A 20141217; JP 2014255558 A 20141217; JP 2015184050 A 20150917; JP 2015184061 A 20150917; JP 2016033027 A 20160224; JP 2016033028 A 20160224; JP 2016033030 A 20160224; KR 20087014775 A 20061120; KR 20137006368 A 20061120; KR 20137009231 A 20061120; KR 20137009234 A 20061120; KR 20147015035 A 20061120; KR 20157000055 A 20061120; KR 20157002473 A 20061120; KR 20157030359 A 20061120; KR 20167033159 A 20061120; KR 20177029140 A 20061120; KR 20187021977 A 20061120; US 2006061113 W 20061120